



# TS IEC 62804-1:2015

Photovoltaic (PV) Modules - Test Methods for the detection of potential-induced degradation  
Part 1: Crystalline silicone  
Confirmation of test results

Ref.: PVMTR-2016-40203-1

Applicant: Changzhou EGing Photovoltaic Technology Co., Ltd.  
No. 18 Jinwu Road, 213213 Jintan City, China

Product: Crystalline silicon Photovoltaic (PV)-Modules

Type:  
A) EG-XXXM60-C  
B) EG-XXXP60-C  
C) EG-XXXM72-C  
D) EG-XXXP72-C

XXX in the type replaces the power in watt and can be any number between:

200 – 320 for A)  
200 – 290 for B)  
240 – 385 for C)  
235 – 350 for D)

Manufacturer: Changzhou EGing Photovoltaic Technology Co., Ltd.

Standard: TS IEC 62804-1:2015

## Test conditions

Testing time:	192 h
Chamber temperature:	85°C
Relative Humidity:	85 %
Potential to ground:	- 1000 V

## Pass criteria

Power degradation:	< 5%
Dry Insulation:	> 40 MΩm <sup>2</sup>
Wet insulation:	> 40 MΩm <sup>2</sup>





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## Summary of test results:

**Maximum power degradation:** required max. 5 %  
measured max. 1.99 %

The measured degradation is below the allowed degradation.

**Dry insulation resistance:** required 24,5 MΩ for A), B)  
measured 20,5 MΩ for C), D)  
>500 MΩ

The measured dry insulation resistance is above the limit.

**Wet insulation resistance:** required 24,5 MΩ for A), B)  
measured 20,5 MΩ for C), D)  
>500 MΩ

The measured wet insulation resistance is above the limit.

**Visual inspection:** No findings

The relevant bill of materials is given in Annex\_1\_PVMTR-2016-40203-1 and Annex\_2\_PVMTR-2016-40203-1.

The complete test results are given in Test Report No.: PVMTR-2016-40203-1.

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